

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	(324/609.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:18
L2	1	(324/602,600.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:18
L3	22	(324/111,522,713.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L4	7	(327/9,55,56,337.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L5	12	(327/50-54.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L6	3	(327/91-96.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L7	7	(341/122-125.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19

L8	8	(341/172.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:19
L9	4	(363/76,78,89.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:20
L10	29	(323/282,353.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:20
L11	30	(455/127.1.ccls.) and @ad<"20040114" and @pd>"20050512"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 11:20
L12	8	(((((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 current) and (resist\$5 FET transistor) and sampl\$3 and switch\$5 and \$4charg\$5 and (convey\$4 feed\$4 advanc\$4 transfer\$4 deliver\$4 rotat\$4 roll\$4) and voltage and (state mode condition status stage) and ground and first and second and third and fourth).clm.) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 12:55
L13	1	("20050151543").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/08/31 13:19
L14	446	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7) near\$3 ((bi\$1 direction\$3 two\$1 way two\$1 direction both\$way both\$1 direction ((two both) adj (way direction))) near\$3 current) and @ad<"20040114"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 13:44

L16	102	114 and ((capacitor sampling) near4 (resist\$5 FET MOSFET BJT transistor))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 13:49
L17	7	114 and (capacitor sampling) same (saml\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 13:46
L18	21	114 and (saml\$3 near2 voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/31 16:01